

# Search Notes



Application/Control No.

10/813,129

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

HIRAMATSU ET AL.

Art Unit

2816

## SEARCHED

Class	Subclass	Date	Examiner
327	143	04.26.05	NA
	198	T	T
	63		
	68		
	72		
	538		
	77		
Updated		06.27.05	NA
Searches			

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	04.18.05	NA
EAST	05.12.05	NA